

Refine Search

Search Results -

Terms	Documents
L14 and (probability near distribut\$4)	0

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search:

L15

Refine Search

Recall Text

Clear

Interrupt

Search History

DATE: Monday, January 10, 2005 [Printable Copy](#) [Create Case](#)

<u>Set Name</u> side by side	<u>Query</u>	<u>Hit Count</u>	<u>Set Name</u> result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			
<u>L15</u>	L14 and (probability near distribut\$4)	0	<u>L15</u>
<u>L14</u>	L13 and ((data near mining) same model)	3	<u>L14</u>
<u>L13</u>	(L9 or L10 or L11) and L1	188	<u>L13</u>
<u>L12</u>	(L9 or L10 or L11) and L4	0	<u>L12</u>
<u>L11</u>	709/225.ccls.	1643	<u>L11</u>
<u>L10</u>	709/219.ccls.	2803	<u>L10</u>
<u>L9</u>	709/218.ccls.	1477	<u>L9</u>
<u>L8</u>	(L6 or L4) and ((data near mining) same model)	2	<u>L8</u>
<u>L7</u>	(L6 or L4) and (data near mining)	4	<u>L7</u>
<u>L6</u>	L5 and L4	3	<u>L6</u>
<u>L5</u>	707/\$.ccls.	24418	<u>L5</u>
<u>L4</u>	L3 and (probability near distribut\$4)	5	<u>L4</u>
<u>L3</u>	L2 and (perturb\$ near data)	17	<u>L3</u>

<u>L2</u>	L1 and perturb\$	347	<u>L2</u>
<u>L1</u>	estimat\$4 and distribut\$4 and (value or data) and (generat\$4 or develop\$3 or creat\$3 or build\$3) and securit\$3	10203	<u>L1</u>

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
(L9 or L10 or L11) and L4	0

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search:

L12

Refine Search

Recall Text

Clear

Interrupt

Search History

 DATE: Monday, January 10, 2005 [Printable Copy](#) [Create Case](#)

<u>Set</u> <u>Name</u>	<u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			
<u>L12</u>	(L9 or L10 or L11) and L4	0	<u>L12</u>
<u>L11</u>	709/225.ccls.	1643	<u>L11</u>
<u>L10</u>	709/219.ccls.	2803	<u>L10</u>
<u>L9</u>	709/218.ccls.	1477	<u>L9</u>
<u>L8</u>	(L6 or L4) and ((data near mining) same model)	2	<u>L8</u>
<u>L7</u>	(L6 or L4) and (data near mining)	4	<u>L7</u>
<u>L6</u>	L5 and L4	3	<u>L6</u>
<u>L5</u>	707/\$.ccls.	24418	<u>L5</u>
<u>L4</u>	L3 and (probability near distribut\$4)	5	<u>L4</u>
<u>L3</u>	L2 and (perturb\$ near data)	17	<u>L3</u>
<u>L2</u>	L1 and perturb\$	347	<u>L2</u>
<u>L1</u>	estimat\$4 and distribut\$4 and (value or data) and (generat\$4 or develop\$3 or creat\$3 or build\$3) and securit\$3	10203	<u>L1</u>

END OF SEARCH HISTORY

THIS PAGE BLANK (USPTO)

Refine Search

Search Results -

Terms	Documents
(L6 or L4) and ((data near mining) same model)	2

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search:

L8

Refine Search

Recall Text

Clear

Interrupt

Search History

DATE: Monday, January 10, 2005 [Printable Copy](#) [Create Case](#)

<u>Set Name</u> side by side	<u>Query</u>	<u>Hit Count</u>	<u>Set Name</u> result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			
<u>L8</u>	(L6 or L4) and ((data near mining) same model)	2	<u>L8</u>
<u>L7</u>	(L6 or L4) and (data near mining)	4	<u>L7</u>
<u>L6</u>	L5 and L4	3	<u>L6</u>
<u>L5</u>	707/\$.ccls.	24418	<u>L5</u>
<u>L4</u>	L3 and (probability near distribut\$4)	5	<u>L4</u>
<u>L3</u>	L2 and (perturb\$ near data)	17	<u>L3</u>
<u>L2</u>	L1 and perturb\$	347	<u>L2</u>
<u>L1</u>	estimat\$4 and distribut\$4 and (value or data) and (generat\$4 or develop\$3 or creat\$3 or build\$3) and securit\$3	10203	<u>L1</u>

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
L3 and (probability near distribut\$4)	5

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search:

L4

Refine Search

Recall Text

Clear

Interrupt

Search History

DATE: Monday, January 10, 2005 [Printable Copy](#) [Create Case](#)

<u>Set</u> <u>Name</u>	<u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>			
<u>L4</u>	L3 and (probability near distribut\$4)	5	<u>L4</u>
<u>L3</u>	L2 and (perturb\$ near data)	17	<u>L3</u>
<u>L2</u>	L1 and perturb\$	347	<u>L2</u>
<u>L1</u>	estimat\$4 and distribut\$4 and (value or data) and (generat\$4 or develop\$3 or creat\$3 or build\$3) and securit\$3	10203	<u>L1</u>

END OF SEARCH HISTORY

Refine Search

Search Results -

Terms	Documents
L5 and L4	3

Database:

US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Search:

L6

Refine Search

Recall Text

Clear

Interrupt

Search History

DATE: Monday, January 10, 2005 [Printable Copy](#) [Create Case](#)

<u>Set</u> <u>Name</u> <u>Query</u>	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>		
<u>L6</u> L5 and L4	3	<u>L6</u>
<u>L5</u> 707/\$.ccls.	24418	<u>L5</u>
<u>L4</u> L3 and (probability near distribut\$4)	5	<u>L4</u>
<u>L3</u> L2 and (perturb\$ near data)	17	<u>L3</u>
<u>L2</u> L1 and perturb\$	347	<u>L2</u>
<u>L1</u> estimat\$4 and distribut\$4 and (value or data) and (generat\$4 or develop\$3 or creat\$3 or build\$3) and securit\$3	10203	<u>L1</u>

END OF SEARCH HISTORY

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE



Membership | Publications/Services | Standards | Conferences | Careers/Jobs

IEEE Xplore®
 RELEASE 1.8

 Welcome
 United States Patent and Trademark Office


» Sea

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)
[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **1** of **1112315** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.

Refine This Search:

You may refine your search by editing the current search expression or entering new one in the text box.

☐ Check to search within this result set

Results Key:

JNL = Journal or Magazine CNF = Conference STD = Standard

1 Privacy-preserving distributed clustering using generative models

Merugu, S.; Joydeep Ghosh;

Data Mining, 2003. ICDM 2003. Third IEEE International Conference on , 19-2 Nov. 2003

Pages:211 - 218

[\[Abstract\]](#)
[\[PDF Full-Text \(483 KB\)\]](#)

IEEE CNF

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office

> Sea

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1112315** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering new one in the text box.

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.** [Print Format](#)[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE


[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)
IEEE Xplore®
RELEASE 1.8

 Welcome
United States Patent and Trademark Office


» Sea

[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)

Quick Links

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced
- ☐ CrossRef

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **0** of **1112315** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering new one in the text box.

perturb* <and> database <and> securit* <and> prob

Search

☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**Results:****No documents matched your query.**

Print Format

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved